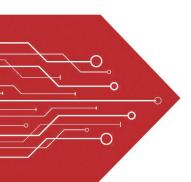
## MSKSEMI















**ESD** 

TVS

**TSS** 

MOV

**GDT** 

**PLED** 

# Broduct data sheet



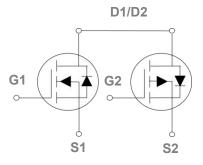






## **TO252-4 Pin Configuration**





#### **Features**

- Fast switching
- Green Device Available
- Suit for 4.5V Gate Drive Applications

## **Applications**

- DC Fan
- Motor Drive Applications
- Networking
- Half / Full Bridge Topology

BVDSS	RDSON	ID
30V	15m $\Omega$	16A
-30V	30m $Ω$	-12A

Symbol	Parameter	Rat	ing	Units	
V <sub>DS</sub>	Drain-Source Voltage	30	-30	V	
V <sub>G</sub> S	Gate-Source Voltage	±20	±20	V	
1_	Drain Current – Continuous (Tc=25°C)	16	-12	Α	
l <sub>D</sub>	Drain Current – Continuous (Tc=100°C)	10.1	-7.6	Α	
Ірм	Drain Current – Pulsed¹	64	-48	Α	
D	Power Dissipation (Tc=25°C)	32	.5	W	
P <sub>D</sub>	Power Dissipation – Derate above 25°C	0.2	0.26		
T <sub>STG</sub>	Storage Temperature Range	-55 to	-55 to 150		
TJ	Operating Junction Temperature Range	-55 to	-55 to 150		

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
R <sub>θJA</sub>	Thermal Resistance Junction to ambient		62.5	°C/W
Rejc	Thermal Resistance Junction to Case		3.84	°C/W





## N-CH Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise) noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
l	Drain-Source Leakage Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
I <sub>DSS</sub>		V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			10	uA
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA

#### **On Characteristics**

R <sub>DS(ON)</sub> Static Drain-Source On-Resistance		V <sub>GS</sub> =10V , I <sub>D</sub> =10A		15	30	mΩ
NDS(ON)	Static Dialii-Source Off-Nesistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		30	40	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.0	1.5	2.5	V
$\Delta V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS, ID-250UA		-4		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =3A		6		S

### **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>3, 4</sup>		 7.4	
Qgs	Gate-Source Charge <sup>3, 4</sup>	$V_{DS}$ =15V , $V_{GS}$ =4.5V , $I_{D}$ =5A	 2.3	nC
$Q_{gd}$	Gate-Drain Charge <sup>3, 4</sup>		 3	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>3, 4</sup>		 3.8	
Tr	Rise Time <sup>3,4</sup>	$V_{DD}$ =15V , $V_{GS}$ =10V , $R_{G}$ =6 $\Omega$	 10	no
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>3, 4</sup>	I <sub>D</sub> =1A	 22	ns
T <sub>f</sub>	Fall Time <sup>3, 4</sup>		 6.6	
Ciss	Input Capacitance		 620	
Coss	Output Capacitance	$V_{DS}$ =25V , $V_{GS}$ =0V , F=1MHz	 85	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 60	
Rg	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz	 2.8	Ω

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V . Force Current			16	Α
Ism	Pulsed Source Current	VG-VD-0V, Force Current			32	Α
$V_{SD}$	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1	V

#### Note:

- Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width  $\leqq 300 us$  , duty cycle  $\leqq 2\%.$
- Essentially independent of operating temperature.



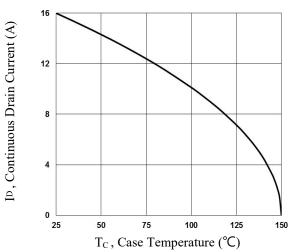


Fig.1 Continuous Drain Current vs. Tc

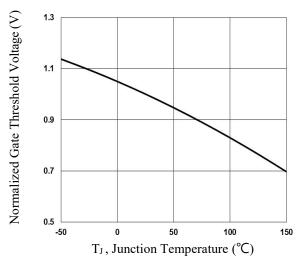


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

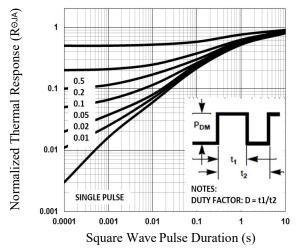


Fig.5 Normalized Transient Response

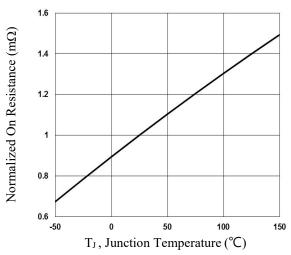


Fig.2 Normalized RDSON vs. T<sub>J</sub>

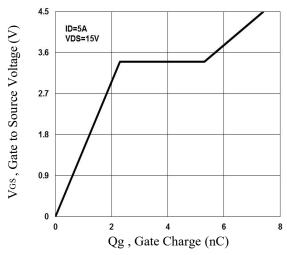


Fig.4 Gate Charge Waveform

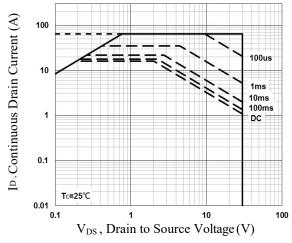


Fig.6 Maximum Safe Operation Area

#### P-CH Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	<b>-</b> 30			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.03		V/°C
1	Drain Source Leekene Current	V <sub>DS</sub> =-30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1	uA
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			-10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA

#### **On Characteristics**

R <sub>DS(ON)</sub> Static Drain-Source On-Resistance		V <sub>GS</sub> =-10V , I <sub>D</sub> =-7A		30	40	mΩ
RDS(ON)		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-4A		45	68	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	\\ \\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	-1	<b>-</b> 1.5	<b>-</b> 2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> = <b>-</b> 250uA		4		mV/°C
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-3A		9		S

## **Dynamic and switching Characteristics**

•				
Qg	Total Gate Charge <sup>2, 3</sup>		 8	
Qgs	Gate-Source Charge <sup>2, 3</sup>	V <sub>DS</sub> =-15V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-5A	 3.3	nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>		 2.3	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2, 3</sup>		 4.6	
Tr	Rise Time <sup>2,3</sup>	$V_{DD}$ =-15V , $V_{GS}$ =-10V , $R_G$ =6 $\Omega$	 14	no
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> =-1A	 34	ns
T <sub>f</sub>	Fall Time <sup>2, 3</sup>		 18	
C <sub>iss</sub>	Input Capacitance		 757	
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , F=1MHz	 122	pF
Crss	Reverse Transfer Capacitance		 88	

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			<b>-</b> 12	Α
I <sub>SM</sub>	Pulsed Source Current	VG-VD-UV, FOICE Current			<b>-</b> 24	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			<b>-</b> 1.2	V

#### Note:

- 4. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- $\begin{array}{ll} 5. & \text{The data tested by pulsed , pulse width} \leqq 300 \text{us , duty cycle} \leqq 2\%. \\ 6. & \text{Essentially independent of operating temperature.} \end{array}$

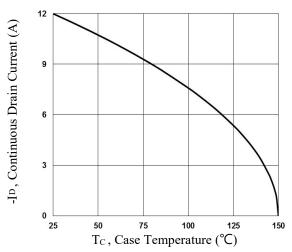


Fig.1 Continuous Drain Current vs. Tc

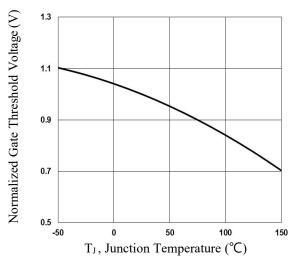


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

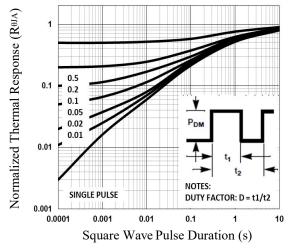


Fig.5 Normalized Transient Impedance

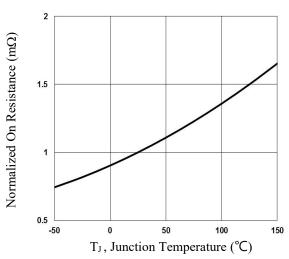


Fig.2 Normalized RDSON vs. T<sub>J</sub>

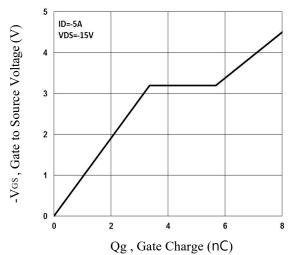


Fig.4 Gate Charge Waveform

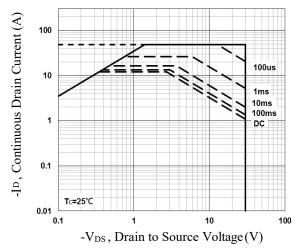
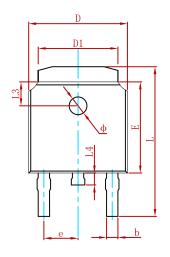


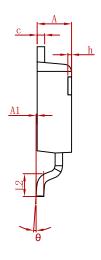
Fig.6 Maximum Safe Operation Area

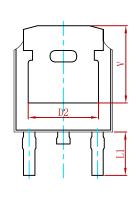




## PACKAGE MECHANICAL DATA

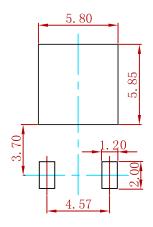






Cumbal	Dimensions	In Millimeters	Dimension	s In Inches	
Symbol	Min.	Max.	Min.	Max.	
Α	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.635	0.770	0.025	0.030	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830	REF.	0.190	REF.	
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.712	10.312	0.382	0.406	
L1	2.900	REF.	0.114	REF.	
L2	1.400	1.700	0.055	0.067	
L3	1.600	REF.	0.063	REF.	
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.250	REF.	0.207 REF.		

## **Suggested Pad Layout**



#### Note:

- 1. Controlling dimension: in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
AOD607-MS	TO-252-4	2500



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BSS340NWH6327XTSA1 MCM3400A-TP DMTH10H4M6SPS-13 IRF40SC240ARMA1 IPS60R1K0PFD7SAKMA1

IPS60R360PFD7SAKMA1 IPS60R600PFD7SAKMA1